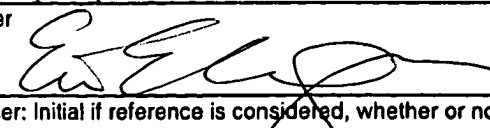



Form PTO 1449 U.S. DEPARTMENT OF COMMERCE (Modified) PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 000004.00682		SERIAL NO. 10/760,418		
LIST OF REFERENCES CITED BY APPLICANT <div style="border: 1px solid black; border-radius: 50%; width: 100px; height: 100px; display: flex; align-items: center; justify-content: center; margin: 0 auto;"> RECEIVED FEB 11 2004 PATENT AND TRADEMARK OFFICE </div>		APPLICANT Ichio AKAMI et al.		GROUP Unassigned		
		FILING DATE January 21, 2004				
U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
EEC	AA 5,168,745	12/08/1992	Miyagawa et al.			
EEC	AB 6,119,503	09/19/2000	Peloquin et al.			
EEC	AC 5,685,191	11/11/1997	Kawano et al.			
	AD					
	AE					
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	AK					
	AL					
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	AN					
FOREIGN PATENT DOCUMENTS						
	DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
EEC	AO 5-7936	January 19, 1993	Japan			X
EEC	AP 0 392 795	October 4, 1990	EPO	X		
EEC	AQ 6-304660	November 1, 1994	Japan	Abstract Only		
EEC	AR 59-88273	May 22, 1984	Japan	Abstract Only		
EEC	AS 09-108738	April 28, 1997	Japan	Abstract Only		
EEC	AT 11-000718	January 6, 1999	Japan	Abstract Only		
EEC	AU 10-225724	August 25, 1998	Japan	Abstract Only		
EEC	AV 07-275941	October 24, 1995	Japan	Abstract Only		
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)						
	AW					
	AX					
	AY					
	AZ					
Examiner 				Date Considered 7/7/04		
<small>*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>						

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	AA					
	AB					
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FOREIGN PATENT DOCUMENTS						
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO	
EEC	AO	55-045288	03-29-80	Japan	Abstract	
EEC	AP	57-37408	1982	Japan	Abstract	
EEC	AQ	63-21932	1988	Japan	Abstract	
EEC	AR	05-187815	1993	Japan	Abstract	
EEC	AS	02-220715	1990	Japan		
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